

High Power RF GaN Amplifier

600 W, 48 V, 2500 - 2700 MHz



MACOM PURE CARBIDE™

MAPC-C27600-CP

Rev. V1

Features

- GaN on SiC HEMT Technology
- Designed for Asymmetrical Doherty Application
- 49.3 dBm Average Output Power
- 600 W Peak Output Power
- Input & Output Pre-matched Device
- Low Thermal Resistance
- 100% DC & RF Tested
- RoHS* Compliant

Applications

- Point-to-Point
- Infrastructure

Description

The MAPC-C27600-CP is a GaN on Silicon Carbide HEMT Amplifier designed for asymmetrical Doherty applications. The device is optimized for the frequency band of 2500 to 2700 MHz. Product is housed in an over-molded TO-package.

Typical Doherty Performance:

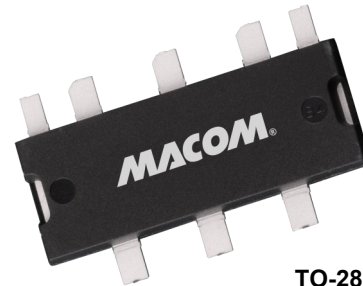
$V_{DS} = 48\text{ V}$, $I_{DQm} = 360\text{ mA}$, $V_{GSpk} = 720\text{ mA} - 1.5\text{ V}$
 $P_{OUT} = 49.3\text{ dBm}$, $T_A = 25^\circ\text{C}$
 Performance in MACOM Doherty Application Fixture.
 Single Carrier- W-CDMA Channel Bandwidth 3.84 MHz,
 PAR 10 dB @ 0.01% CCDF.

Frequency (MHz)	Gain (dB)	Efficiency (%)	Output PAR (dB)	ACPR (dBc)
2496	14.7	54	8.7	-29
2593	15	54	9.0	-31
2690	15	54	8.5	-32

Ordering Information

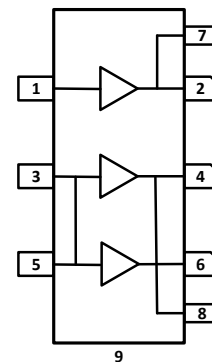
Part Number	Package
MAPC-C27600-CPTR1	50 pc Tape and Reel ¹
MAPC-C27600-CPTR2	250 pc Tape and Reel ¹
MAPC-C27600-CPSB1	Sample Board

1. See application note AN-0004525 for tape and reel information.



TO-288-8L

Functional Schematic



Pin Configuration

Pin #	Pin Name	Function
1	RF _{IN} / V _{G1}	RF Input / Gate (Main)
2	RF _{OUT} / V _{D1}	RF Output / Drain (Main)
3, 5	RF _{IN} / V _{G2}	RF Input / Gate (Peak)
4, 6	RF _{OUT} / V _{D2}	RF Output / Drain (Peak)
7, 8	VBW Lead	Drain Video Decoupling. No DC Bias
9	Flange ²	Ground / Source

2. The flange on the package bottom must be connected to RF, DC and thermal ground.

1 * Restrictions on Hazardous Substances, compliant to current RoHS EU directive.

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RF Electrical Characterization:

Freq. = 2690 MHz, P_{OUT} = 49.3 dBm, T_A = 25°C, V_{DS} = 48 V, I_{DQM} = 360 mA, V_{GSPK} = 720 mA –1.5 V

Note: Performance in MACOM Doherty Application Fixture. Single Carrier- W-CDMA Channel Bandwidth 3.84 MHz, PAR 10 dB @ 0.01% CCDF.

Parameter	Test Conditions	Symbol	Min.	Typ.	Max.	Units
Power Gain	—	G _p	—	15	—	dB
Drain Efficiency	—	η	—	54	—	%
Output CCDF @ 0.01%	—	PAR	—	8.5	—	dB
Adjacent Channel Power	—	ACP	—	-32	—	dBc
Input Return Loss	—	IRL	—	-18	—	dB
Gain Flatness	—	G _F	—	0.5	—	dB
Gain Variation (-40°C to +105°C)	—	ΔG	—	0.02	—	dB/°C
Power Variation (-40°C to +105°C)	Pulsed 10% DC	ΔP _{3dB}	—	0.006	—	dB/°C
Ruggedness: Output Mismatch	All phase angles	Ψ	VSWR =10:1, No Device Damage			

RF Electrical Test Specifications:

Freq. = 2690 MHz, P_{OUT} = 49.3 dBm, T_A = 25°C, V_{DS} = 48 V, I_{DQM} = 360 mA, V_{GSPK} = 720 mA –1.5 V

Note: Performance in MACOM Doherty Production Test Fixture. Single Carrier- W-CDMA Channel Bandwidth 3.84 MHz, PAR 10 dB @ 0.01% CCDF.

Parameter	Test Conditions	Symbol	Min.	Typ.	Max.	Units
Power Gain	—	G _p	12	14	—	dB
Drain Efficiency	—	η	41	52	—	%
Output CCDF @ 0.01%	—	PAR	6.9	8.4	—	dB
Adjacent Channel Power	—	ACP	—	-31	-22	dBc

DC Electrical Characteristics $T_A = +25^\circ\text{C}$

Parameter	Test Conditions	Symbol	Min.	Typ.	Max.	Units
Main Amplifier						
Gate-Source Leakage Current	$V_{GS} = -8\text{ V}, V_{DS} = 50\text{ V}$	I_{GLK}	—	-0.054	—	mA
Gate-Source Leakage Current	$V_{GS} = -8\text{ V}, V_{DS} = 100\text{ V}$	I_{GLK}	-2.5	—	—	mA
Gate Threshold Voltage	$V_{DS} = 10\text{ V}, I_D = 36\text{ mA}$	V_T	-3.8	-2.8	—	V
Gate Quiescent Voltage	$V_{DS} = 48\text{ V}, I_D = 360\text{ mA}$	V_{GSQ}	—	-3.2	—	V
On Resistance	$V_{GS} = 0\text{ V}, V_{DS} = 0.1\text{ V}, I_D = 100\text{ mA}$	R_{ON}	—	0.093	—	Ω
Peak Amplifier						
Gate-Source Leakage Current	$V_{GS} = -8\text{ V}, V_{DS} = 50\text{ V}$	I_{GLK}	—	-0.18	—	mA
Gate-Source Leakage Current	$V_{GS} = -8\text{ V}, V_{DS} = 100\text{ V}$	I_{GLK}	-5	—	—	mA
Gate Threshold Voltage	$V_{DS} = 10\text{ V}, I_D = 72\text{ mA}$	V_T	-3.8	-2.8	—	V
Gate Quiescent Voltage	$V_{DS} = 48\text{ V}, I_D = 720\text{ mA}$	V_{GSQ}	—	-3.2	—	V
On Resistance	$V_{GS} = 0\text{ V}, V_{DS} = 0.1\text{ V}, I_D = 100\text{ mA}$	R_{ON}	—	0.044	—	Ω

Recommended Operating Voltages

Parameter	Test Conditions	Units	Min.	Typ.	Max.
Drain Operating Voltage	—	V	—	—	50
Gate Quiescent Voltage	$V_{DS} = 48\text{ V}, I_D = 360\text{ mA}$	V	-3.6	-2.9	-2.1

Moisture Sensitivity Level

Level	Test Standard	Package Temperature	Unit
3	IPC/JEDEC J-STD-020	260	$^\circ\text{C}$

Absolute Maximum Ratings^{5,6,7,8,9}

Parameter	Absolute Maximum
Drain Source Voltage, V_{DS}	100 V
Gate Source Voltage, V_{GS}	-10 to 2 V
Gate Current (Main), I_G	36 mA
Gate Current (Peak), I_G	72 mA
Storage Temperature Range	-65°C to +150°C
Case Operating Temperature Range	-40°C to +125°C
Channel Operating Temperature Range, T_{CH}	-40°C to +225°C
Absolute Maximum Channel Temperature	+225°C

- Exceeding any one or combination of these limits may cause permanent damage to this device.
- MACOM does not recommend sustained operation above maximum operating conditions.
- Operating at drain source voltage $V_{DS} < 55V$ will ensure $MTTF > 2.51 \times 10^6$ hours.
- Operating at nominal conditions with $T_{CH} \leq 225^\circ C$ will ensure $MTTF > 2.51 \times 10^6$ hours.
- MTTF may be estimated by the expression $MTTF \text{ (hours)} = A e^{[B + C/(T+273)]}$ where T is the channel temperature in degrees Celsius., $A = 1.93$, $B = -45.31$, and $C = 29,585$.

Thermal Characteristics¹⁰

Parameter	Test Conditions	Symbol	Typical	Units
Thermal Resistance using Infrared Measurement of Die Surface Temperature	$P_{DISS} = 131 W$ $T_C = +85^\circ C, T_{CH} = +225^\circ C$	$R_{\theta}(IR)$	1.07	°C/W

- Case temperature measured using thermocouple embedded in heat-sink. Contact local applications support team for more details on this measurement.

Bias Sequencing

Bias ON

- Ensure RF is turned off
- Apply pinch-off voltage of -5 V to the gate
- Apply nominal drain voltage
- Bias gate to desired quiescent drain current
- Apply RF

Bias OFF

- Turn RF off
- Apply pinch-off voltage to the gate
- Turn-off drain voltage
- Turn-off gate voltage

Handling Procedures

Please observe the following precautions to avoid damage:

Static Sensitivity

Gallium Nitride Circuits are sensitive to electrostatic discharge (ESD) and can be damaged by static electricity. Proper ESD control techniques should be used when handling these devices.

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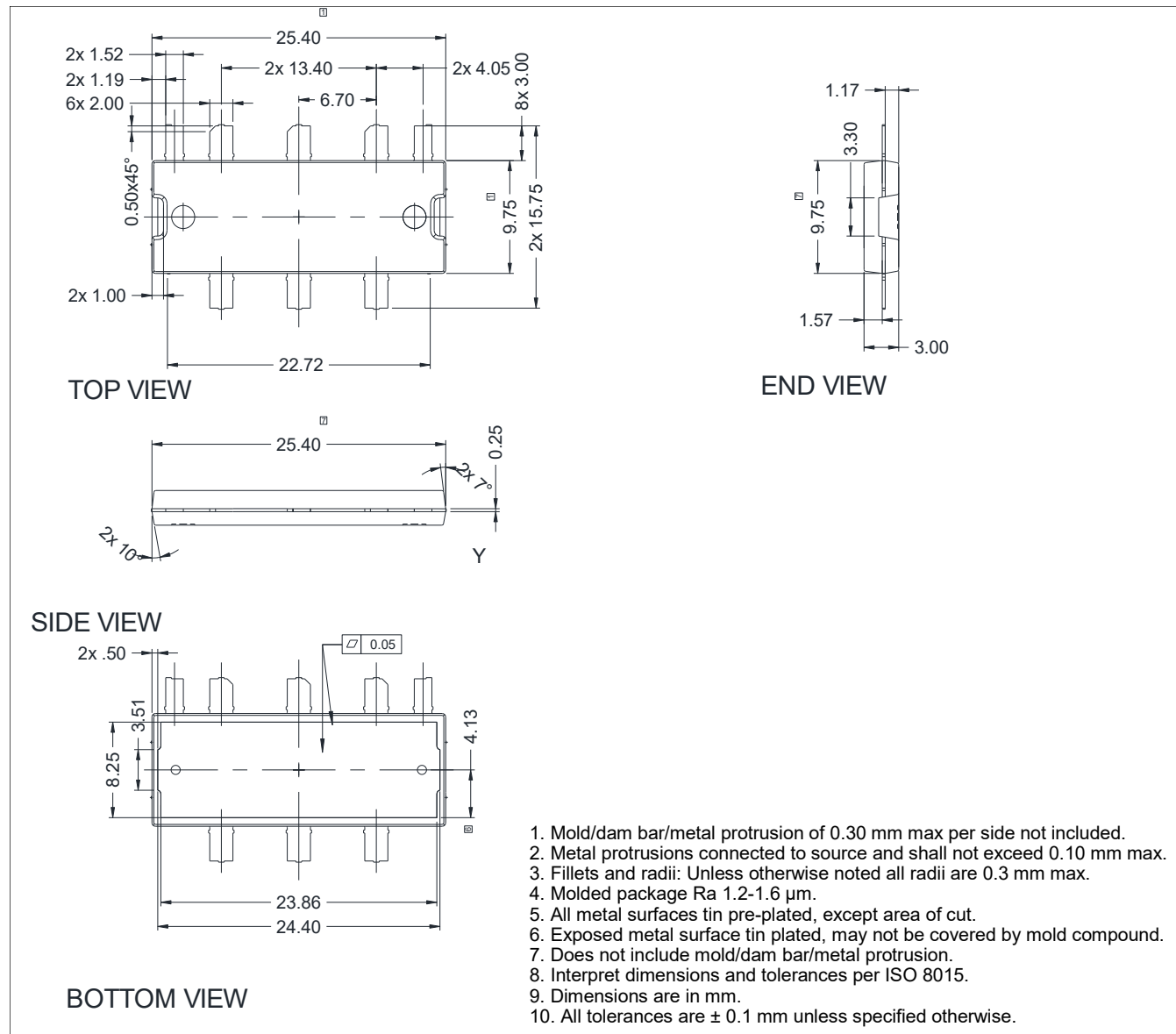


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TO-288-8L Package Dimensions



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